

Silicon PIN diode

FEATURES

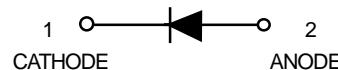
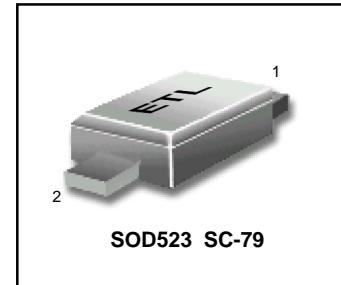
- High voltage, current controlled
- RF resistor for RF attenuators and switches
- Low diode capacitance
- Low diode forward resistance
- Very low series inductance
- For applications up to 3 GHz.

APPLICATIONS

- RF attenuators and switches.

DESCRIPTION

Planar PIN diode in a SOD523 ultra small plastic SMD package.

BAP64 – 02


LIMITING VALUES In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_R	continuous reverse voltage		–	175	V
I_F	continuous forward current		–	100	mA
P_{tot}	total power dissipation	$T_s = 90^\circ\text{C}$	–	715	mW
T_{stg}	storage temperature		-65	+150	°C
T_j	junction temperature		-65	+150	°C

ELECTRICAL CHARACTERISTICS $T_j = 25^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
V_F	forward voltage	$I_F = 50 \text{ mA}$	0.95	1.1	V
I_R	reverse current	$V_R = 175 \text{ V}$	–	10	μA
		$V_R = 20 \text{ V}$	–	1	μA
C_d	diode capacitance	$V_R = 0; f = 1 \text{ MHz}$	0.48	–	pF
		$V_R = 1 \text{ V}; f = 1 \text{ MHz}$	0.35	–	pF
		$V_R = 20 \text{ V}; f = 1 \text{ MHz}$	0.23	0.35	pF
r_D	diode forward resistance	$I_F = 0.5 \text{ mA}; f = 100 \text{ MHz}; \text{note 1}$	20	40	Ω
		$I_F = 1 \text{ mA}; f = 100 \text{ MHz}; \text{note 1}$	10	20	Ω
		$I_F = 10 \text{ mA}; f = 100 \text{ MHz}; \text{note 1}$	2	3.8	Ω
		$I_F = 100 \text{ mA}; f = 100 \text{ MHz}; \text{note 1}$	0.7	1.35	Ω
τ_L	charge carrier life time	when switched from $I_F = 10 \text{ mA}$ to $I_R = 6 \text{ mA}; R_L = 100 \Omega$; measured at $I_R = 3 \text{ mA}$	1.55	–	μs
L_s	series inductance		0.6	–	nH

Note 1. Guaranteed on AQL basis: inspection level S4, AQL 1.0.

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
$R_{th,j-s}$	thermal resistance from junction to soldering-point	85	K/W

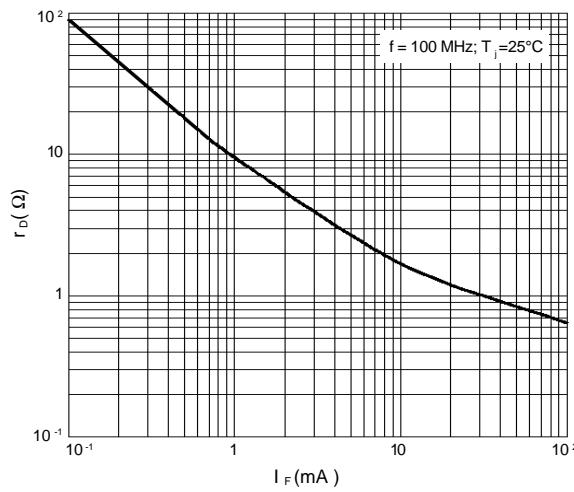


Fig.1 Forward resistance as a function of forward current; typical values.

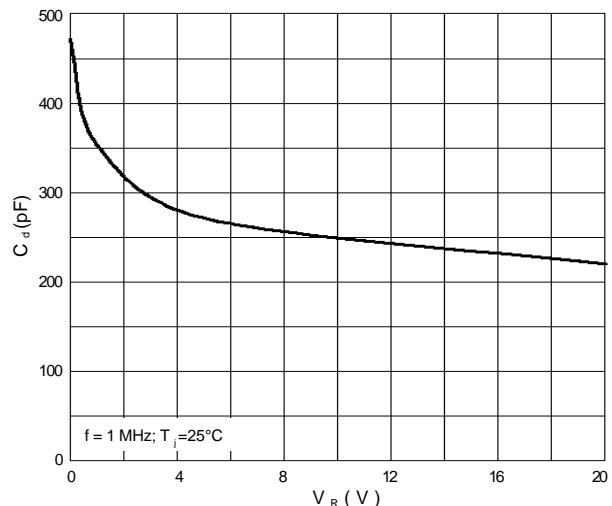


Fig.2 Diode capacitance as a function of reverse voltage; typical values.

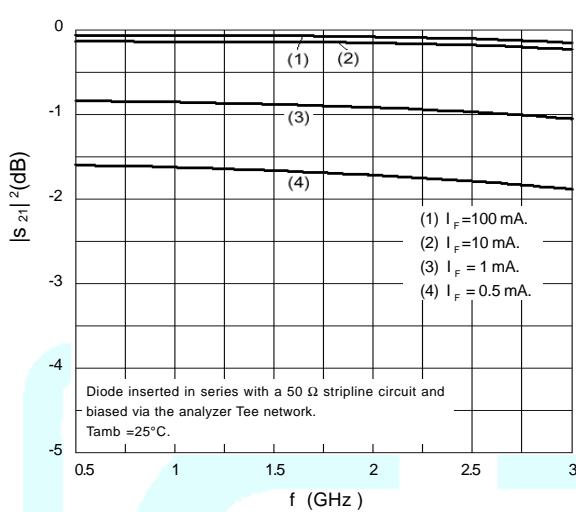


Fig.3 Insertion loss ($|S_{21}|^2$) of the diode in on-state as a function of frequency; typical values.

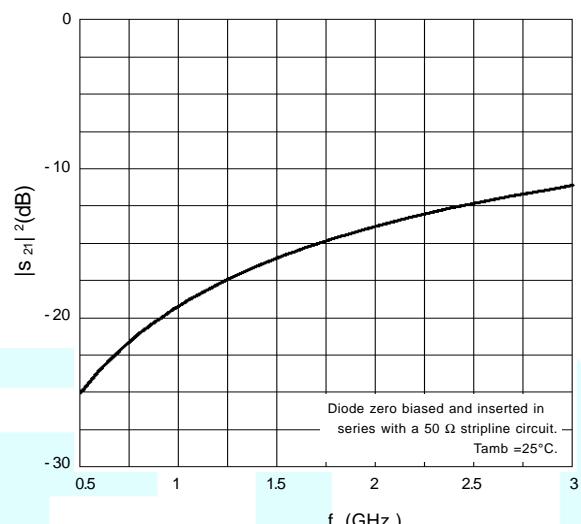


Fig.4 Isolation ($|S_{21}|^2$) of the diode in off-state as a function of frequency; typical values.

SEMICONDUCTOR